

<b>Notice of References Cited</b>	Application/Control No. 10/807,450	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
	Examiner John B. Nguyen	Art Unit 2819	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,839,643 B2	01-2005	Kanke et al.	702/45
	B	US-6,664,761 B2	12-2003	Yudahira et al.	320/116
	C	US-6,285,191 B1	09-2001	Gollomp et al.	324/427
	D	US-5,329,111	07-1994	Sonoda et al.	250/208.1
	E	US-2004/0244478 A1	12-2004	Kanke et al.	073/204.15
	F	US-6,801,247 B1	10-2004	Ohishi et al.	348/208.1
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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